Features

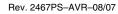
- High-performance, Low-power AVR® 8-bit Microcontroller
- Advanced RISC Architecture
 - 133 Powerful Instructions Most Single Clock Cycle Execution
 - 32 x 8 General Purpose Working Registers + Peripheral Control Registers
 - Fully Static Operation
 - Up to 16 MIPS Throughput at 16 MHz
 - On-chip 2-cycle Multiplier
- High Endurance Non-volatile Memory segments
 - 128K Bytes of In-System Self-programmable Flash program memory
 - 4K Bytes EEPROM
 - 4K Bytes Internal SRAM
 - Write/Erase cycles: 10,000 Flash/100,000 EEPROM
 - Data retention: 20 years at 85°C/100 years at 25°C⁽¹⁾
 - Optional Boot Code Section with Independent Lock Bits In-System Programming by On-chip Boot Program True Read-While-Write Operation
 - Up to 64K Bytes Optional External Memory Space
 - Programming Lock for Software Security
 - SPI Interface for In-System Programming
- JTAG (IEEE std. 1149.1 Compliant) Interface
 - Boundary-scan Capabilities According to the JTAG Standard
 - Extensive On-chip Debug Support
 - Programming of Flash, EEPROM, Fuses and Lock Bits through the JTAG Interface
- Peripheral Features
 - Two 8-bit Timer/Counters with Separate Prescalers and Compare Modes
 - Two Expanded 16-bit Timer/Counters with Separate Prescaler, Compare Mode and Capture Mode
 - Real Time Counter with Separate Oscillator
 - Two 8-bit PWM Channels
 - 6 PWM Channels with Programmable Resolution from 2 to 16 Bits
 - Output Compare Modulator
 - 8-channel, 10-bit ADC
 - 8 Single-ended Channels
 - 7 Differential Channels
 - 2 Differential Channels with Programmable Gain at 1x, 10x, or 200x
 - Byte-oriented Two-wire Serial Interface
 - Dual Programmable Serial USARTs
 - Master/Slave SPI Serial Interface
 - Programmable Watchdog Timer with On-chip Oscillator
 - On-chip Analog Comparator
- Special Microcontroller Features
 - Power-on Reset and Programmable Brown-out Detection
 - Internal Calibrated RC Oscillator
 - External and Internal Interrupt Sources
 - Six Sleep Modes: Idle, ADC Noise Reduction, Power-save, Power-down, Standby, and Extended Standby
 - Software Selectable Clock Frequency
 - ATmega103 Compatibility Mode Selected by a Fuse
 - Global Pull-up Disable
- I/O and Packages
 - 53 Programmable I/O Lines
 - 64-lead TQFP and 64-pad QFN/MLF
- Operating Voltages
 - 2.7 5.5V for ATmega128L
 - 4.5 5.5V for ATmega128
- Speed Grades
 - 0 8 MHz for ATmega128L
 - 0 16 MHz for ATmega128



8-bit AVR®
Microcontroller
with 128K Bytes
In-System
Programmable
Flash

ATmega128 ATmega128L

Summary



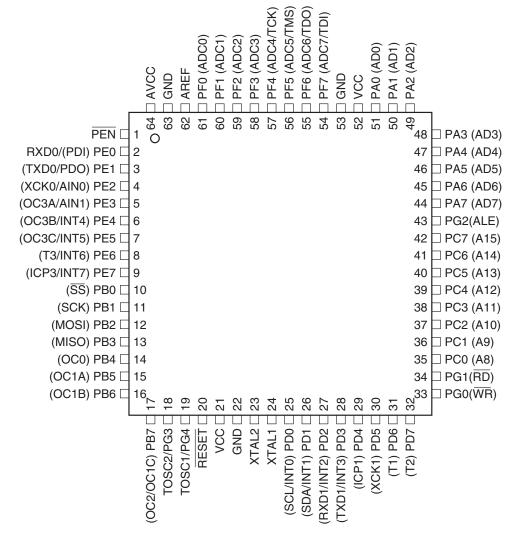




Pin Figur

Figure 1. Pinout ATmega128

Configurations



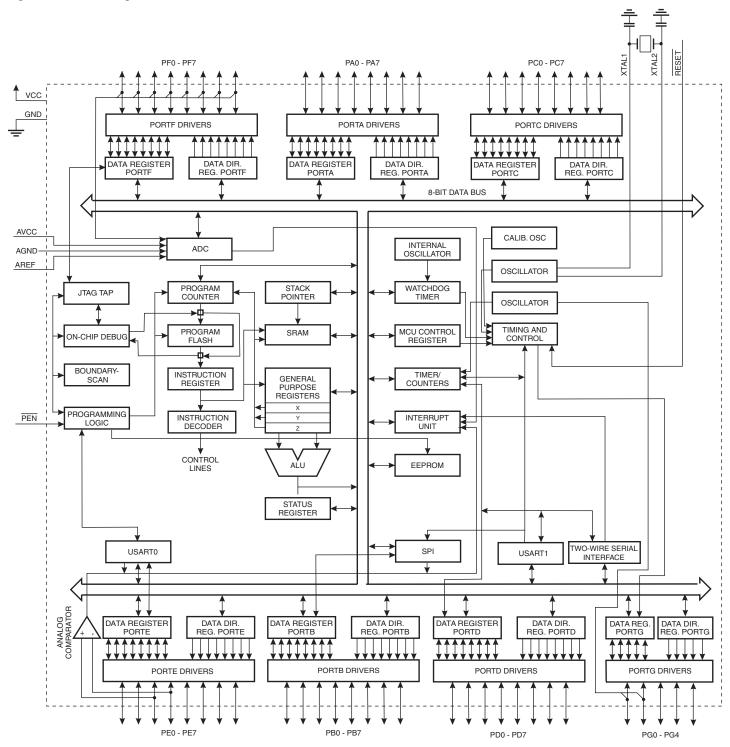
Note: The Pinout figure applies to both TQFP and MLF packages. The bottom pad under the QFN/MLF package should be soldered to ground.

Overview

The ATmega128 is a low-power CMOS 8-bit microcontroller based on the AVR enhanced RISC architecture. By executing powerful instructions in a single clock cycle, the ATmega128 achieves throughputs approaching 1 MIPS per MHz allowing the system designer to optimize power consumption versus processing speed.

Block Diagram

Figure 2. Block Diagram







The AVR core combines a rich instruction set with 32 general purpose working registers. All the 32 registers are directly connected to the Arithmetic Logic Unit (ALU), allowing two independent registers to be accessed in one single instruction executed in one clock cycle. The resulting architecture is more code efficient while achieving throughputs up to ten times faster than conventional CISC microcontrollers.

The ATmega128 provides the following features: 128K bytes of In-System Programmable Flash with Read-While-Write capabilities, 4K bytes EEPROM, 4K bytes SRAM, 53 general purpose I/O lines, 32 general purpose working registers, Real Time Counter (RTC), four flexible Timer/Counters with compare modes and PWM, 2 USARTs, a byte oriented Two-wire Serial Interface, an 8-channel, 10-bit ADC with optional differential input stage with programmable gain, programmable Watchdog Timer with Internal Oscillator, an SPI serial port, IEEE std. 1149.1 compliant JTAG test interface, also used for accessing the On-chip Debug system and programming and six software selectable power saving modes. The Idle mode stops the CPU while allowing the SRAM, Timer/Counters, SPI port, and interrupt system to continue functioning. The Power-down mode saves the register contents but freezes the Oscillator, disabling all other chip functions until the next interrupt or Hardware Reset. In Power-save mode, the asynchronous timer continues to run, allowing the user to maintain a timer base while the rest of the device is sleeping. The ADC Noise Reduction mode stops the CPU and all I/O modules except Asynchronous Timer and ADC, to minimize switching noise during ADC conversions. In Standby mode, the Crystal/Resonator Oscillator is running while the rest of the device is sleeping. This allows very fast start-up combined with low power consumption. In Extended Standby mode, both the main Oscillator and the Asynchronous Timer continue to run.

The device is manufactured using Atmel's high-density nonvolatile memory technology. The Onchip ISP Flash allows the program memory to be reprogrammed in-system through an SPI serial interface, by a conventional nonvolatile memory programmer, or by an On-chip Boot program running on the AVR core. The boot program can use any interface to download the application program in the application Flash memory. Software in the Boot Flash section will continue to run while the Application Flash section is updated, providing true Read-While-Write operation. By combining an 8-bit RISC CPU with In-System Self-Programmable Flash on a monolithic chip, the Atmel ATmega128 is a powerful microcontroller that provides a highly flexible and cost effective solution to many embedded control applications.

The ATmega128 AVR is supported with a full suite of program and system development tools including: C compilers, macro assemblers, program debugger/simulators, in-circuit emulators, and evaluation kits.

ATmega103 and ATmega128 Compatibility

The ATmega128 is a highly complex microcontroller where the number of I/O locations supersedes the 64 I/O locations reserved in the AVR instruction set. To ensure backward compatibility with the ATmega103, all I/O locations present in ATmega103 have the same location in ATmega128. Most additional I/O locations are added in an Extended I/O space starting from \$60 to \$FF, (i.e., in the ATmega103 internal RAM space). These locations can be reached by using LD/LDS/LDD and ST/STS/STD instructions only, not by using IN and OUT instructions. The relocation of the internal RAM space may still be a problem for ATmega103 users. Also, the increased number of interrupt vectors might be a problem if the code uses absolute addresses. To solve these problems, an ATmega103 compatibility mode can be selected by programming the fuse M103C. In this mode, none of the functions in the Extended I/O space are in use, so the internal RAM is located as in ATmega103. Also, the Extended Interrupt vectors are removed.

The ATmega128 is 100% pin compatible with ATmega103, and can replace the ATmega103 on current Printed Circuit Boards. The application note "Replacing ATmega103 by ATmega128" describes what the user should be aware of replacing the ATmega103 by an ATmega128.

ATmega103 Compatibility Mode

By programming the M103C fuse, the ATmega128 will be compatible with the ATmega103 regards to RAM, I/O pins and interrupt vectors as described above. However, some new features in ATmega128 are not available in this compatibility mode, these features are listed below:

- One USART instead of two, Asynchronous mode only. Only the eight least significant bits of the Baud Rate Register is available.
- One 16 bits Timer/Counter with two compare registers instead of two 16-bit Timer/Counters with three compare registers.
- Two-wire serial interface is not supported.
- Port C is output only.
- Port G serves alternate functions only (not a general I/O port).
- Port F serves as digital input only in addition to analog input to the ADC.
- Boot Loader capabilities is not supported.
- It is not possible to adjust the frequency of the internal calibrated RC Oscillator.
- The External Memory Interface can not release any Address pins for general I/O, neither configure different wait-states to different External Memory Address sections.

In addition, there are some other minor differences to make it more compatible to ATmega103:

- Only EXTRF and PORF exists in MCUCSR.
- Timed sequence not required for Watchdog Time-out change.
- External Interrupt pins 3 0 serve as level interrupt only.
- USART has no FIFO buffer, so data overrun comes earlier.

Unused I/O bits in ATmega103 should be written to 0 to ensure same operation in ATmega128.

Pin Descriptions

VCC

Digital supply voltage.

GND

Ground.

Port A (PA7..PA0)

Port A is an 8-bit bi-directional I/O port with internal pull-up resistors (selected for each bit). The Port A output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port A pins that are externally pulled low will source current if the pull-up resistors are activated. The Port A pins are tri-stated when a reset condition becomes active, even if the clock is not running.

Port A also serves the functions of various special features of the ATmega128 as listed on page 73.

Port B (PB7..PB0)

Port B is an 8-bit bi-directional I/O port with internal pull-up resistors (selected for each bit). The Port B output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port B pins that are externally pulled low will source current if the pull-up resistors are activated. The Port B pins are tri-stated when a reset condition becomes active, even if the clock is not running.

Port B also serves the functions of various special features of the ATmega128 as listed on page 74.

Port C (PC7..PC0)

Port C is an 8-bit bi-directional I/O port with internal pull-up resistors (selected for each bit). The Port C output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port C pins that are externally pulled low will source current if the pull-up





resistors are activated. The Port C pins are tri-stated when a reset condition becomes active, even if the clock is not running.

Port C also serves the functions of special features of the ATmega128 as listed on page 77. In ATmega103 compatibility mode, Port C is output only, and the port C pins are **not** tri-stated when a reset condition becomes active.

Note:

The ATmega128 is by default shipped in ATmega103 compatibility mode. Thus, if the parts are not programmed before they are put on the PCB, PORTC will be output during first power up, and until the ATmega103 compatibility mode is disabled.

Port D (PD7..PD0)

Port D is an 8-bit bi-directional I/O port with internal pull-up resistors (selected for each bit). The Port D output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port D pins that are externally pulled low will source current if the pull-up resistors are activated. The Port D pins are tri-stated when a reset condition becomes active, even if the clock is not running.

Port D also serves the functions of various special features of the ATmega128 as listed on page 78.

Port E (PE7..PE0)

Port E is an 8-bit bi-directional I/O port with internal pull-up resistors (selected for each bit). The Port E output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port E pins that are externally pulled low will source current if the pull-up resistors are activated. The Port E pins are tri-stated when a reset condition becomes active, even if the clock is not running.

Port E also serves the functions of various special features of the ATmega128 as listed on page 81.

Port F (PF7..PF0)

Port F serves as the analog inputs to the A/D Converter.

Port F also serves as an 8-bit bi-directional I/O port, if the A/D Converter is not used. Port pins can provide internal pull-up resistors (selected for each bit). The Port F output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port F pins that are externally pulled low will source current if the pull-up resistors are activated. The Port F pins are tri-stated when a reset condition becomes active, even if the clock is not running. If the JTAG interface is enabled, the pull-up resistors on pins PF7(TDI), PF5(TMS), and PF4(TCK) will be activated even if a Reset occurs.

The TDO pin is tri-stated unless TAP states that shift out data are entered.

Port F also serves the functions of the JTAG interface.

In ATmega103 compatibility mode, Port F is an input Port only.

Port G (PG4..PG0)

Port G is a 5-bit bi-directional I/O port with internal pull-up resistors (selected for each bit). The Port G output buffers have symmetrical drive characteristics with both high sink and source capability. As inputs, Port G pins that are externally pulled low will source current if the pull-up resistors are activated. The Port G pins are tri-stated when a reset condition becomes active, even if the clock is not running.

Port G also serves the functions of various special features.

The port G pins are tri-stated when a reset condition becomes active, even if the clock is not running.

In ATmega103 compatibility mode, these pins only serves as strobes signals to the external memory as well as input to the 32 kHz Oscillator, and the pins are initialized to PG0 = 1, PG1 = 1, and PG2 = 0 asynchronously when a reset condition becomes active, even if the clock is not running. PG3 and PG4 are oscillator pins.

ATmega128(L)

RESET Reset input. A low level on this pin for longer than the minimum pulse length will generate a

reset, even if the clock is not running. The minimum pulse length is given in Table 19 on page

51. Shorter pulses are not guaranteed to generate a reset.

XTAL1 Input to the inverting Oscillator amplifier and input to the internal clock operating circuit.

XTAL2 Output from the inverting Oscillator amplifier.

AVCC is the supply voltage pin for Port F and the A/D Converter. It should be externally con-

nected to V_{CC} , even if the ADC is not used. If the ADC is used, it should be connected to V_{CC}

through a low-pass filter.

AREF AREF is the analog reference pin for the A/D Converter.

PEN PEN is a programming enable pin for the SPI Serial Programming mode, and is internally pulled

high . By holding this pin low during a Power-on Reset, the device will enter the SPI Serial Pro-

gramming mode. PEN has no function during normal operation.





Resources

A comprehensive set of development tools, application notes, and datasheets are available for download on http://www.atmel.com/avr.

Data Retention

Reliability Qualification results show that the projected data retention failure rate is much less than 1 PPM over 20 years at 85°C or 100 years at 25°C.

Register Summary

										_
Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	Page
(\$FF)	Reserved	_	-	_	_	_	-	-	_	
	Reserved	-	-	_	-	-	_	-	-	
(\$9E)	Reserved	-	=	_	-	=	-	-	=	
(\$9D)	UCSR1C	-	UMSEL1	UPM11	UPM10	USBS1	UCSZ11	UCSZ10	UCPOL1	191
(\$9C)	UDR1				USART1 I/C	Data Register				189
(\$9B)	UCSR1A	RXC1	TXC1	UDRE1	FE1	DOR1	UPE1	U2X1	MPCM1	189
(\$9A)	UCSR1B	RXCIE1	TXCIE1	UDRIE1	RXEN1	TXEN1	UCSZ12	RXB81	TXB81	190
(\$99)	UBRR1L				USART1 Baud	Rate Register Lo	w			192
(\$98)	UBRR1H	-	-	_	-		USART1 Baud I	Rate Register High	1	192
(\$97)	Reserved	-	-	_	-	-	-	-	-	
(\$96)	Reserved	-	-	-	-	-	-	-	-	
(\$95)	UCSR0C	_	UMSEL0	UPM01	UPM00	USBS0	UCSZ01	UCSZ00	UCPOL0	191
(\$94)	Reserved	_	-	_	-	-	-	_	_	
(\$93)	Reserved	_	-	_	-	_	-	_	_	
(\$92)	Reserved	_	-	_	_	-	-	-	_	
(\$91)	Reserved	_	-	_	-	_	_	_	_	
(\$90)	UBRR0H	-	-	-	-			Rate Register Higl	า 1	192
(\$8F)	Reserved	-	-	_	-	-	-	-	-	
(\$8E)	Reserved	_	-	_	-	_	-	-	-	
(\$8D)	Reserved	-	-	-	-	_	_	-	_	
(\$8C)	TCCR3C	FOC3A	FOC3B	FOC3C	-	_	-	-	_	137
(\$8B)	TCCR3A	COM3A1	COM3A0	COM3B1	COM3B0	COM3C1	COM3C0	WGM31	WGM30	133
(\$8A)	TCCR3B	ICNC3	ICES3	_	WGM33	WGM32	CS32	CS31	CS30	136
(\$89)	TCNT3H				er/Counter3 – Co					138
(\$88)	TCNT3L				er/Counter3 – Co					138
(\$87)	OCR3AH				unter3 – Output C					138
(\$86)	OCR3AL		Timer/Counter3 – Output Compare Register A Low Byte						138	
(\$85)	OCR3BH				unter3 – Output C					139
(\$84)	OCR3BL				unter3 – Output C					139
(\$83)	OCR3CH		Timer/Counter3 – Output Compare Register C High Byte Timer/Counter3 – Output Compare Register C Low Byte					139		
(\$82)	OCR3CL									139
(\$81)	ICR3H				Counter3 - Input					139
(\$80) (\$7F)	ICR3L	_	_	- Inner/	Counter3 – Input	Capture Register	Low Byte	_	_	139
(\$7E)	Reserved				_	_	_			
(\$7D)	Reserved ETIMSK	_	_	TICIE3	OCIE3A	OCIE3B	TOIE3	OCIE3C	OCIE1C	140
(\$7C)	ETIFR	_		ICF3	OCF3A	OCF3B	TOV3	OCF3C	OCF1C	141
(\$7B)	Reserved	_	_	-	- OCI 3A	— — — — — — — — — — — — — — — — — — —	-	-	-	141
(\$7A)	TCCR1C	FOC1A	FOC1B	FOC1C	_	_	_	_	_	137
(\$79)	OCR1CH	10017	10015		unter1 – Output C		C High Byte			138
(\$78)	OCR1CL				unter1 – Output C					138
(\$77)	Reserved	_	_	-	_		-	_	_	100
(\$76)	Reserved	_	_	_	_	_	_	_	_	
(\$75)	Reserved	_	_	_	_	_	_	_	_	
(\$74)	TWCR	TWINT	TWEA	TWSTA	TWSTO	TWWC	TWEN	-	TWIE	206
(\$73)	TWDR				Two-wire Serial In					208
(\$72)	TWAR	TWA6	TWA5	TWA4	TWA3	TWA2	TWA1	TWA0	TWGCE	208
(\$71)	TWSR	TWS7	TWS6	TWS5	TWS4	TWS3	_	TWPS1	TWPS0	207
(\$70)	TWBR		•		o-wire Serial Inte		gister		-	206
(\$6F)	OSCCAL					ibration Register	-			42
(\$6E)	Reserved	-	_	_	_	_	_	_	_	
(\$6D)	XMCRA	_	SRL2	SRL1	SRL0	SRW01	SRW00	SRW11		31
(\$6C)	XMCRB	XMBK	-	_	_	_	XMM2	XMM1	XMM0	33
(\$6B)	Reserved	-	-	_	-	_	_	-	-	
(\$6A)	EICRA	ISC31	ISC30	ISC21	ISC20	ISC11	ISC10	ISC01	ISC00	90
(\$69)	Reserved	-	-	-	-	-	=	-	-	
(\$68)	SPMCSR	SPMIE	RWWSB	_	RWWSRE	BLBSET	PGWRT	PGERS	SPMEN	277
(\$67)	Reserved	-	-	-	-	-	-	-	-	
(\$66)	Reserved	_	-		-	-		-	-	
(\$65)	PORTG	-	-	_	PORTG4	PORTG3	PORTG2	PORTG1	PORTG0	89
(\$64)	DDRG	_	-		DDG4	DDG3	DDG2	DDG1	DDG0	89
(\$63)	PING	_	-		PING4	PING3	PING2	PING1	PING0	89
(\$62)	PORTF	PORTF7	PORTF6	PORTF5	PORTF4	PORTF3	PORTF2	PORTF1	PORTF0	88





Register Summary (Continued)

										_
Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	Page
(\$61)	DDRF	DDF7	DDF6	DDF5	DDF4	DDF3	DDF2	DDF1	DDF0	89
(\$60)	Reserved	-	-	-	_	-	-	-	_	
\$3F (\$5F)	SREG	I	T	Н	S	V	N	Z	С	11
\$3E (\$5E)	SPH	SP15	SP14	SP13	SP12	SP11	SP10	SP9	SP8	14
\$3D (\$5D)	SPL	SP7	SP6	SP5	SP4	SP3	SP2	SP1	SP0	14
\$3C (\$5C)	XDIV	XDIVEN	XDIV6	XDIV5	XDIV4	XDIV3	XDIV2	XDIV1	XDIV0	37
\$3B (\$5B)	RAMPZ	-	-	-	-	-	-	-	RAMPZ0	14
\$3A (\$5A)	EICRB	ISC71	ISC70 INT6	ISC61	ISC60	ISC51	ISC50	ISC41	ISC40	91 91
\$39 (\$59) \$38 (\$58)	EIMSK EIFR	INT7 INTF7	INTF6	INT5 INTF5	INT4 INTF4	INT3 INTF3	INT2 INTF	INT1 INTF1	INT0 INTF0	92
\$37 (\$57)	TIMSK	OCIE2	TOIE2	TICIE1	OCIE1A	OCIE1B	TOIE1	OCIE0	TOIE0	109, 139, 159
\$36 (\$56)	TIFR	OCF2	TOV2	ICF1	OCF1A	OCF1B	TOV1	OCF0	TOV0	109, 141, 159
\$35 (\$55)	MCUCR	SRE	SRW10	SE	SM1	SM0	SM2	IVSEL	IVCE	31, 45, 64
\$34 (\$54)	MCUCSR	JTD	-	_	JTRF	WDRF	BORF	EXTRF	PORF	54, 254
\$33 (\$53)	TCCR0	FOC0	WGM00	COM01	COM00	WGM01	CS02	CS01	CS00	104
\$32 (\$52)	TCNT0				Timer/Co	unter0 (8 Bit)				106
\$31 (\$51)	OCR0			Ti	mer/Counter0 Ou	tput Compare Re	gister			106
\$30 (\$50)	ASSR	-	-	-	-	AS0	TCN0UB	OCR0UB	TCR0UB	107
\$2F (\$4F)	TCCR1A	COM1A1	COM1A0	COM1B1	COM1B0	COM1C1	COM1C0	WGM11	WGM10	133
\$2E (\$4E)	TCCR1B	ICNC1	ICES1		WGM13	WGM12	CS12	CS11	CS10	136
\$2D (\$4D)	TCNT1H				er/Counter1 – Cou					138
\$2C (\$4C)	TCNT1L	-			er/Counter1 – Co					138
\$2B (\$4B)	OCR1AH OCR1AL				unter1 – Output C					138 138
\$2A (\$4A) \$29 (\$49)	OCR1BH				unter1 – Output C unter1 – Output C		•			138
\$28 (\$48)	OCR1BL				unter1 - Output C		<u> </u>			138
\$27 (\$47)	ICR1H				Counter1 - Input					139
\$26 (\$46)	ICR1L		Timer/Counter1 – Input Capture Register Low Byte						139	
\$25 (\$45)	TCCR2	FOC2	WGM20	COM21	COM20	WGM21	CS22	CS21	CS20	157
\$24 (\$44)	TCNT2				Timer/Cou	unter2 (8 Bit)				159
\$23 (\$43)	OCR2			Ti	mer/Counter2 Out	tput Compare Re	gister			159
\$22 (\$42)	OCDR	IDRD/OCDR7	OCDR6	OCDR5	OCDR4	OCDR3	OCDR2	OCDR1	OCDR0	251
\$21 (\$41)	WDTCR	-	-	-	WDCE	WDE	WDP2	WDP1	WDP0	56
\$20 (\$40)	SFIOR	TSM	-	_	-	ACME	PUD	PSR0	PSR321	73, 110, 144, 227
\$1F (\$3F)	EEARH	-	-	_	-	<u> </u>		ess Register High	<u> </u>	21
\$1E (\$3E) \$1D (\$3D)	EEARL EEDR				EEPROM Addres		yte			21 22
\$1C (\$3C)	EECR	_	_	_	EEPHOWI	Data Register EERIE	EEMWE	EEWE	EERE	22
\$1B (\$3B)	PORTA	PORTA7	PORTA6	PORTA5	PORTA4	PORTA3	PORTA2	PORTA1	PORTA0	87
\$1A (\$3A)	DDRA	DDA7	DDA6	DDA5	DDA4	DDA3	DDA2	DDA1	DDA0	87
\$19 (\$39)	PINA	PINA7	PINA6	PINA5	PINA4	PINA3	PINA2	PINA1	PINA0	87
\$18 (\$38)	PORTB	PORTB7	PORTB6	PORTB5	PORTB4	PORTB3	PORTB2	PORTB1	PORTB0	87
\$17 (\$37)	DDRB	DDB7	DDB6	DDB5	DDB4	DDB3	DDB2	DDB1	DDB0	87
\$16 (\$36)	PINB	PINB7	PINB6	PINB5	PINB4	PINB3	PINB2	PINB1	PINB0	87
\$15 (\$35)	PORTC	PORTC7	PORTC6	PORTC5	PORTC4	PORTC3	PORTC2	PORTC1	PORTC0	87
\$14 (\$34)	DDRC	DDC7	DDC6	DDC5	DDC4	DDC3	DDC2	DDC1	DDC0	87
\$13 (\$33)	PINC	PINC7	PINC6	PINC5	PINC4	PINC3	PINC2	PINC1	PINC0	88
\$12 (\$32)	PORTD	PORTD7	PORTD6	PORTD5	PORTD4	PORTD3	PORTD2	PORTD1	PORTD0	88
\$11 (\$31)	DDRD	DDD7	DDD6	DDD5	DDD4	DDD3	DDD2	DDD1	DDD0	88
\$10 (\$30) \$0F (\$2F)	PIND SPDR	PIND7	PIND6	PIND5	PIND4	PIND3 ta Register	PIND2	PIND1	PIND0	160
\$0F (\$2F) \$0E (\$2E)	SPSR	SPIF	WCOL	_	SPI Da	a negisier	_	_	SPI2X	169 169
\$0D (\$2D)	SPCR	SPIE	SPE	DORD	MSTR	CPOL	CPHA	SPR1	SPR0	167
\$0C (\$2C)	UDR0	O. IL	J 0, L	2010		Data Register	J. TIA	J 51111	51 110	189
\$0B (\$2B)	UCSR0A	RXC0	TXC0	UDRE0	FE0	DOR0	UPE0	U2X0	MPCM0	189
\$0A (\$2A)	UCSR0B	RXCIE0	TXCIE0	UDRIE0	RXEN0	TXEN0	UCSZ02	RXB80	TXB80	190
\$09 (\$29)	UBRR0L					Rate Register Lo				192
\$08 (\$28)	ACSR	ACD	ACBG	ACO	ACI	ACIE	ACIC	ACIS1	ACIS0	227
\$07 (\$27)	ADMUX	REFS1	REFS0	ADLAR	MUX4	MUX3	MUX2	MUX1	MUX0	242
\$06 (\$26)	ADCSRA	ADEN	ADSC	ADFR	ADIF	ADIE	ADPS2	ADPS1	ADPS0	244
\$05 (\$25)	ADCH					egister High Byte				245
\$04 (\$24)	ADCL	ļ	1	1		egister Low byte	1	1	T	245
\$03 (\$23)	PORTE	PORTE7	PORTE6	PORTE5	PORTE4	PORTE3	PORTE2	PORTE1	PORTE0	88
\$02 (\$22)	DDRE	DDE7	DDE6	DDE5	DDE4	DDE3	DDE2	DDE1	DDE0	88

Register Summary (Continued)

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	Page
\$01 (\$21)	PINE	PINE7	PINE6	PINE5	PINE4	PINE3	PINE2	PINE1	PINE0	88
\$00 (\$20)	PINF	PINF7	PINF6	PINF5	PINF4	PINF3	PINF2	PINF1	PINF0	89

Notes: 1. For compatibility with future devices, reserved bits should be written to zero if accessed. Reserved I/O memory addresses should never be written.

2. Some of the status flags are cleared by writing a logical one to them. Note that the CBI and SBI instructions will operate on all bits in the I/O register, writing a one back into any flag read as set, thus clearing the flag. The CBI and SBI instructions work with registers \$00 to \$1F only.





Instruction Set Summary

Mnemonics	Operands	Description	Operation	Flags	#Clocks
ARITHMETIC AND	LOGIC INSTRUCTION	S	'		
ADD	Rd, Rr	Add two Registers	Rd ← Rd + Rr	Z,C,N,V,H	1
ADC	Rd, Rr	Add with Carry two Registers	$Rd \leftarrow Rd + Rr + C$	Z,C,N,V,H	1
ADIW	Rdl,K	Add Immediate to Word	Rdh:Rdl ← Rdh:Rdl + K	Z,C,N,V,S	2
SUB	Rd, Rr	Subtract two Registers	Rd ← Rd - Rr	Z,C,N,V,H	1
SUBI	Rd, K	Subtract Constant from Register	Rd ← Rd - K	Z,C,N,V,H	1
SBC	Rd, Rr	Subtract with Carry two Registers	Rd ← Rd - Rr - C	Z,C,N,V,H	1
SBCI	Rd, K	Subtract with Carry Constant from Reg.	Rd ← Rd - K - C	Z,C,N,V,H	1
SBIW	Rdl,K	Subtract Immediate from Word	Rdh:Rdl ← Rdh:Rdl - K	Z,C,N,V,S	2
AND	Rd, Rr	Logical AND Registers	Rd ← Rd • Rr	Z,N,V	1
ANDI	Rd, K	Logical AND Register and Constant	$Rd \leftarrow Rd \bullet K$	Z,N,V	1
OR	Rd, Rr	Logical OR Registers	Rd ← Rd v Rr	Z,N,V	1
ORI	Rd, K	Logical OR Register and Constant	Rd ← Rd v K	Z,N,V	1
EOR	Rd, Rr	Exclusive OR Registers	Rd ← Rd ⊕ Rr	Z,N,V	1
COM	Rd	One's Complement	Rd ← \$FF – Rd	Z,C,N,V	1
NEG	Rd	Two's Complement	Rd ← \$00 – Rd	Z,C,N,V,H	1
SBR	Rd,K	Set Bit(s) in Register	Rd ← Rd v K	Z,N,V	1
CBR	Rd,K	Clear Bit(s) in Register	Rd ← Rd • (\$FF - K)	Z,N,V	1
INC	Rd	Increment	Rd ← Rd + 1	Z,N,V	1
DEC	Rd	Decrement	Rd ← Rd + 1 Rd ← Rd - 1	Z,N,V	1
TST	Rd	Test for Zero or Minus	Rd ← Rd • Rd	Z,N,V	1
	Rd	 	Rd ← Rd ⊕ Rd	Z,N,V Z,N,V	1
CLR		Clear Register			
SER	Rd	Set Register	Rd ← \$FF	None	2
MUL	Rd, Rr	Multiply Unsigned	R1:R0 ← Rd x Rr	Z,C	
MULS	Rd, Rr	Multiply Signed	R1:R0 ← Rd x Rr	Z,C	2
MULSU	Rd, Rr	Multiply Signed with Unsigned	R1:R0 ← Rd x Rr	Z,C	2
FMUL	Rd, Rr	Fractional Multiply Unsigned	$R1:R0 \leftarrow (Rd \times Rr) << 1$	Z,C	2
FMULS	Rd, Rr	Fractional Multiply Signed	R1:R0 ← (Rd x Rr) << 1	Z,C	2
FMULSU	Rd, Rr	Fractional Multiply Signed with Unsigned	R1:R0 ← (Rd x Rr) << 1	Z,C	2
BRANCH INSTRUC				1	Г
RJMP	k	Relative Jump	PC ← PC + k + 1	None	2
IJMP		Indirect Jump to (Z)	PC ← Z	None	2
JMP	k	Direct Jump	PC ← k	None	3
RCALL	k	Relative Subroutine Call	PC ← PC + k + 1	None	3
ICALL		Indirect Call to (Z)	PC ← Z	None	3
CALL	k	Direct Subroutine Call	PC ← k	None	4
RET		Subroutine Return	PC ← STACK	None	4
RETI		Interrupt Return	PC ← STACK	1	4
CPSE	Rd,Rr	Compare, Skip if Equal	if (Rd = Rr) PC ← PC + 2 or 3	None	1/2/3
CP	Rd,Rr	Compare	Rd – Rr	Z, N,V,C,H	1
CPC	Rd,Rr	Compare with Carry	Rd – Rr – C	Z, N,V,C,H	1
CPI	Rd,K	Compare Register with Immediate	Rd – K	Z, N,V,C,H	1
SBRC	Rr, b	Skip if Bit in Register Cleared	if (Rr(b)=0) PC ← PC + 2 or 3	None	1/2/3
SBRS	Rr, b	Skip if Bit in Register is Set	if (Rr(b)=1) PC ← PC + 2 or 3	None	1/2/3
SBIC	P, b	Skip if Bit in I/O Register Cleared	if (P(b)=0) PC ← PC + 2 or 3	None	1/2/3
SBIS	P, b	Skip if Bit in I/O Register is Set	if (P(b)=1) PC ← PC + 2 or 3	None	1/2/3
BRBS	s, k	Branch if Status Flag Set	if (SREG(s) = 1) then PC←PC+k + 1	None	1/2
BRBC	s, k	Branch if Status Flag Cleared	if (SREG(s) = 0) then PC←PC+k + 1	None	1/2
BREQ	k	Branch if Equal	if $(Z = 1)$ then $PC \leftarrow PC + k + 1$	None	1/2
BRNE	k	Branch if Not Equal	if (Z = 0) then PC ← PC + k + 1	None	1/2
BRCS	k	Branch if Carry Set	if (C = 1) then PC ← PC + k + 1	None	1/2
BRCC	k	Branch if Carry Cleared	if (C = 0) then PC ← PC + k + 1	None	1/2
BRSH	k	Branch if Same or Higher	if (C = 0) then PC \leftarrow PC + k + 1	None	1/2
BRLO	k	Branch if Lower	if (C = 1) then PC \leftarrow PC + k + 1	None	1/2
BRMI	k	Branch if Minus	if (N = 1) then PC ← PC + k + 1	None	1/2
BRPL	k	Branch if Plus	if (N = 0) then PC \leftarrow PC + k + 1	None	1/2
BRGE	k	Branch if Greater or Equal, Signed	if $(N \oplus V = 0)$ then $PC \leftarrow PC + k + 1$	None	1/2
BRLT	k	Branch if Less Than Zero, Signed	if $(N \oplus V = 0)$ then $PC \leftarrow PC + k + 1$ if $(N \oplus V = 1)$ then $PC \leftarrow PC + k + 1$	None	1/2
	k	Branch if Half Carry Flag Set			
BRHS		, ,	if (H = 1) then PC \leftarrow PC + k + 1	None	1/2
BRHC	k	Branch if Half Carry Flag Cleared	if (H = 0) then PC ← PC + k + 1	None	1/2
BRTS	k	Branch if T Flag Set	if (T = 1) then PC ← PC + k + 1	None	1/2
BRTC	k	Branch if T Flag Cleared	if (T = 0) then PC ← PC + k + 1	None	1/2
BRVS	k	Branch if Overflow Flag is Set	if (V = 1) then PC ← PC + k + 1	None	1/2
BRVC	k	Branch if Overflow Flag is Cleared	if (V = 0) then PC ← PC + k + 1	None	1/2

Instruction Set Summary (Continued)

Mnemonics	Operands	Description	Operation	Flags	#Clocks
BRIE	k	Branch if Interrupt Enabled	if (I = 1) then PC \leftarrow PC + k + 1	None	1/2
BRID	k	Branch if Interrupt Disabled	if (I = 0) then PC ← PC + k + 1	None	1/2
DATA TRANSFER	INSTRUCTIONS	_			
MOV	Rd, Rr	Move Between Registers	Rd ← Rr	None	1
MOVW	Rd, Rr	Copy Register Word	Rd+1:Rd ← Rr+1:Rr	None	1
LDI	Rd, K	Load Immediate	Rd ← K	None	1
LD	Rd, X	Load Indirect	$Rd \leftarrow (X)$	None	2
LD	Rd, X+	Load Indirect and Post-Inc.	$Rd \leftarrow (X), X \leftarrow X + 1$	None	2
LD	Rd, - X	Load Indirect and Pre-Dec.	$X \leftarrow X - 1$, $Rd \leftarrow (X)$	None	2
LD	Rd, Y	Load Indirect	$Rd \leftarrow (Y)$	None	2
LD	Rd, Y+ Rd, - Y	Load Indirect and Post-Inc. Load Indirect and Pre-Dec.	$Rd \leftarrow (Y), Y \leftarrow Y + 1$ $Y \leftarrow Y - 1, Rd \leftarrow (Y)$	None	2 2
LDD	Rd,Y+q	Load Indirect with Displacement	$Rd \leftarrow (Y + q)$	None None	2
LD	Rd, Z	Load Indirect Load Indirect	$Rd \leftarrow (7 + 4)$ $Rd \leftarrow (Z)$	None	2
LD	Rd, Z+	Load Indirect and Post-Inc.	$Rd \leftarrow (Z), Z \leftarrow Z+1$	None	2
LD	Rd, -Z	Load Indirect and Pre-Dec.	$Z \leftarrow Z - 1$, $Rd \leftarrow (Z)$	None	2
LDD	Rd, Z+q	Load Indirect with Displacement	$Rd \leftarrow (Z + q)$	None	2
LDS	Rd, k	Load Direct from SRAM	$Rd \leftarrow (k)$	None	2
ST	X, Rr	Store Indirect	$(X) \leftarrow Rr$	None	2
ST	X+, Rr	Store Indirect and Post-Inc.	$(X) \leftarrow Rr, X \leftarrow X + 1$	None	2
ST	- X, Rr	Store Indirect and Pre-Dec.	$X \leftarrow X - 1$, $(X) \leftarrow Rr$	None	2
ST	Y, Rr	Store Indirect	(Y) ← Rr	None	2
ST	Y+, Rr	Store Indirect and Post-Inc.	$(Y) \leftarrow Rr, Y \leftarrow Y + 1$	None	2
ST	- Y, Rr	Store Indirect and Pre-Dec.	$Y \leftarrow Y - 1$, $(Y) \leftarrow Rr$	None	2
STD	Y+q,Rr	Store Indirect with Displacement	$(Y + q) \leftarrow Rr$	None	2
ST	Z, Rr	Store Indirect	(Z) ← Rr	None	2
ST	Z+, Rr	Store Indirect and Post-Inc.	$(Z) \leftarrow Rr, Z \leftarrow Z + 1$	None	2
ST	-Z, Rr	Store Indirect and Pre-Dec.	$Z \leftarrow Z - 1$, $(Z) \leftarrow Rr$	None	2
STD	Z+q,Rr	Store Indirect with Displacement	$(Z+q) \leftarrow Rr$	None	2
STS	k, Rr	Store Direct to SRAM	(k) ← Rr	None	2
LPM		Load Program Memory	R0 ← (Z)	None	3
LPM	Rd, Z	Load Program Memory	Rd ← (Z)	None	3
LPM	Rd, Z+	Load Program Memory and Post-Inc	$Rd \leftarrow (Z), Z \leftarrow Z+1$	None	3
ELPM	D4 7	Extended Load Program Memory	$R0 \leftarrow (RAMPZ:Z)$	None	3
ELPM ELPM	Rd, Z Rd, Z+	Extended Load Program Memory Extended Load Program Memory and Post-Inc	Rd \leftarrow (RAMPZ:Z) Rd \leftarrow (RAMPZ:Z), RAMPZ:Z \leftarrow RAMPZ:Z+1	None None	3
SPM	nu, Z+	Store Program Memory	$(Z) \leftarrow R1:R0$	None	
IN	Rd, P	In Port	Rd ← P	None	1
OUT	P, Rr	Out Port	P ← Rr	None	1
PUSH	Rr	Push Register on Stack	STACK ← Rr	None	2
POP	Rd	Pop Register from Stack	Rd ← STACK	None	2
BIT AND BIT-TEST	•				•
SBI	P,b	Set Bit in I/O Register	I/O(P,b) ← 1	None	2
CBI	P,b	Clear Bit in I/O Register	I/O(P,b) ← 0	None	2
LSL	Rd	Logical Shift Left	$Rd(n+1) \leftarrow Rd(n), Rd(0) \leftarrow 0$	Z,C,N,V	1
LSR	Rd	Logical Shift Right	$Rd(n) \leftarrow Rd(n+1), Rd(7) \leftarrow 0$	Z,C,N,V	1
ROL	Rd	Rotate Left Through Carry	$Rd(0)\leftarrow C,Rd(n+1)\leftarrow Rd(n),C\leftarrow Rd(7)$	Z,C,N,V	1
ROR	Rd	Rotate Right Through Carry	$Rd(7)\leftarrow C,Rd(n)\leftarrow Rd(n+1),C\leftarrow Rd(0)$	Z,C,N,V	1
ASR	Rd	Arithmetic Shift Right	$Rd(n) \leftarrow Rd(n+1), n=06$	Z,C,N,V	1
SWAP	Rd	Swap Nibbles	Rd(30)←Rd(74),Rd(74)←Rd(30)	None	1
BSET	s	Flag Set	SREG(s) ← 1	SREG(s)	1
BCLR	s	Flag Clear	SREG(s) ← 0	SREG(s)	1
BST	Rr, b	Bit Store from Register to T	T ← Rr(b)	T	1
BLD	Rd, b	Bit load from T to Register	$Rd(b) \leftarrow T$	None	1
SEC		Set Carry	C ← 1	С	1
CLC		Clear Carry	C ← 0	C	1
SEN		Set Negative Flag	N ← 1	N	1
CLN	1	Clear Negative Flag	N ← 0	N	1
SEZ	+	Set Zero Flag	Z←1	Z	1
CLZ	+	Clear Zero Flag	Z ← 0	Z	1
SEI		Global Interrupt Enable	I ← 1	+ -	1
SES	1	Global Interrupt Disable Set Signed Test Flag	I ← 0 S ← 1	S	1
CLS	+	Clear Signed Test Flag	S ← 1 S ← 0	S	1
OLO		Olean Signed Test Liay	3 ← 0	J	_ '





Instruction Set Summary (Continued)

Mnemonics	Operands	Description	Operation	Flags	#Clocks
SEV		Set Twos Complement Overflow.	V ← 1	V	1
CLV		Clear Twos Complement Overflow	V ← 0	V	1
SET		Set T in SREG	T ← 1	T	1
CLT		Clear T in SREG	T ← 0	Т	1
SEH		Set Half Carry Flag in SREG	H ← 1	Н	1
CLH		Clear Half Carry Flag in SREG	H ← 0	Н	1
MCU CONTROL INS	TRUCTIONS				
NOP		No Operation		None	1
SLEEP		Sleep	(see specific descr. for Sleep function)	None	1
WDR		Watchdog Reset	(see specific descr. for WDR/timer)	None	1
BREAK		Break	For On-chip Debug Only	None	N/A

Ordering Information

Speed (MHz)	Power Supply	Ordering Code	Package ⁽¹⁾	Operation Range	
		ATmega128L-8AC	64A	Commercial	
		ATmega128L-8MC	64M1	(0°C to 70°C)	
8	2.7 - 5.5V	ATmega128L-8AI	64A		
0	2.7 - 5.5V	ATmega128L-8AU ⁽²⁾	64A	Industrial	
		ATmega128L-8MI	64M1	(-40°C to 85°C)	
		ATmega128L-8MU ⁽²⁾	64M1		
		ATmega128-16AC	64A	Commercial	
		ATmega128-16MC	64M1	(0°C to 70°C)	
16	4.5 - 5.5V	ATmega128-16AI	64A		
	4.5 - 5.5 V	ATmega128-16AU ⁽²⁾	64A	Industrial	
		ATmega128-16MI	64M1	(-40°C to 85°C)	
		ATmega128-16MU ⁽²⁾	64M1		

Notes: 1. The device can also be supplied in wafer form. Please contact your local Atmel sales office for detailed ordering information and minimum quantities.

2. Pb-free packaging alternative, complies to the European Directive for Restriction of Hazardous Substances (RoHS directive). Also Halide free and fully Green.

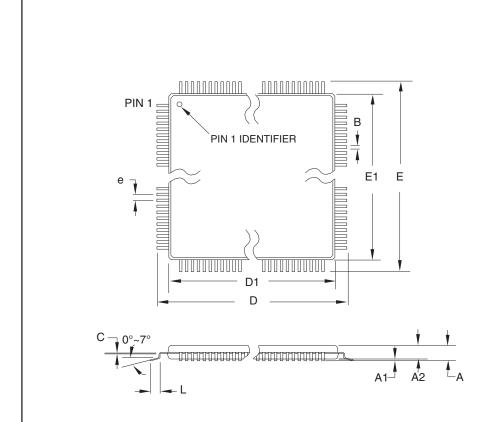
Package Type					
64 A	64-lead, 14 x 14 x 1.0 mm, Thin Profile Plastic Quad Flat Package (TQFP)				
64M1	64-pad, 9 x 9 x 1.0 mm, Quad Flat No-Lead/Micro Lead Frame Package (QFN/MLF)				





Packaging Information

64A



1.This package conforms to JEDEC reference MS-026, Variation AEB.2. Dimensions D1 and E1 do not include mold protrusion. Allowable protrusion is 0.25 mm per side. Dimensions D1 and E1 are maximum

plastic body size dimensions including mold mismatch.

3. Lead coplanarity is 0.10 mm maximum.

COMMON DIMENSIONS

(Unit of Measure = mm)

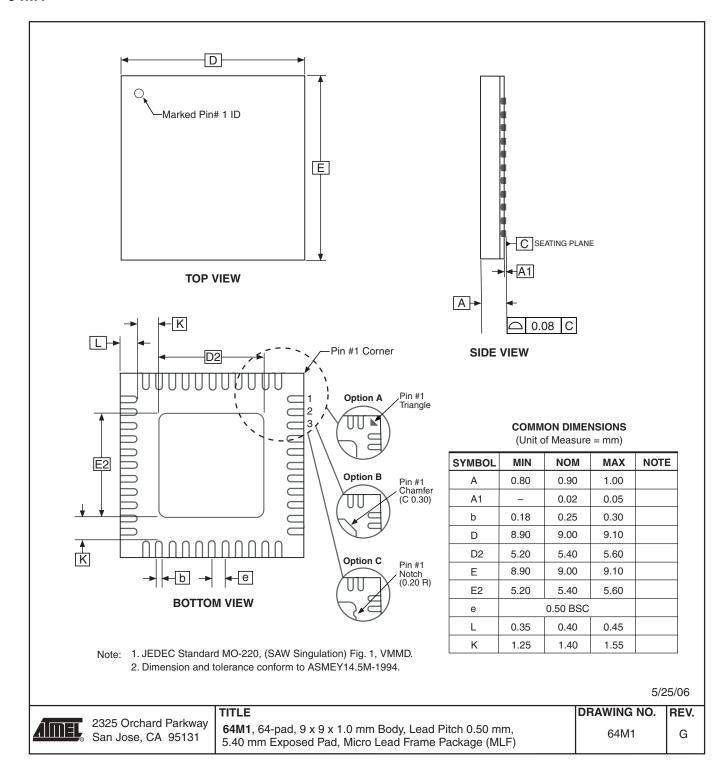
SYMBOL	MIN	NOM	MAX	NOTE
Α	-	_	1.20	
A1	0.05	_	0.15	
A2	0.95	1.00	1.05	
D	15.75	16.00	16.25	
D1	13.90	14.00	14.10	Note 2
Е	15.75	16.00	16.25	
E1	13.90	14.00	14.10	Note 2
В	0.30	_	0.45	
С	0.09	_	0.20	
L	0.45	_	0.75	
е				

10/5/2001

2325 Orchard Parkway San Jose, CA 95131 **TITLE 64A**, 64-lead, 14 x 14 mm Body Size, 1.0 mm Body Thickness, 0.8 mm Lead Pitch, Thin Profile Plastic Quad Flat Package (TQFP)

DRAWING NO. REV. 64A B

64M1





Errata

The revision letter in this section refers to the revision of the ATmega128 device.

ATmega128 Rev. M

- First Analog Comparator conversion may be delayed
- Interrupts may be lost when writing the timer registers in the asynchronous timer
- Stabilizing time needed when changing XDIV Register
- Stabilizing time needed when changing OSCCAL Register
- IDCODE masks data from TDI input
- Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request

1. First Analog Comparator conversion may be delayed

If the device is powered by a slow rising V_{CC} , the first Analog Comparator conversion will take longer than expected on some devices.

Problem Fix/Workaround

When the device has been powered or reset, disable then enable the Analog Comparator before the first conversion.

2. Interrupts may be lost when writing the timer registers in the asynchronous timer

If one of the timer registers which is synchronized to the asynchronous timer2 clock is written in the cycle before a overflow interrupt occurs, the interrupt may be lost.

Problem Fix/Workaround

Always check that the Timer2 Timer/Counter register, TCNT2, does not have the value 0xFF before writing the Timer2 Control Register, TCCR2, or Output Compare Register, OCR2

3. Stabilizing time needed when changing XDIV Register

After increasing the source clock frequency more than 2% with settings in the XDIV register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The NOP instruction will always be executed correctly also right after a frequency change. Thus, the next 8 instructions after the change should be NOP instructions. To ensure this, follow this procedure:

- 1.Clear the I bit in the SREG Register.
- 2.Set the new pre-scaling factor in XDIV register.
- 3. Execute 8 NOP instructions
- 4.Set the I bit in SREG

This will ensure that all subsequent instructions will execute correctly.

Assembly Code Example:

```
CLI
                   ; clear global interrupt enable
OUT
     XDIV, temp
                   ; set new prescale value
NOP
                   ; no operation
SEI
                   ; set global interrupt enable
```

4. Stabilizing time needed when changing OSCCAL Register

After increasing the source clock frequency more than 2% with settings in the OSCCAL register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The behavior follows errata number 3., and the same Fix / Workaround is applicable on this errata.

5. IDCODE masks data from TDI input

The JTAG instruction IDCODE is not working correctly. Data to succeeding devices are replaced by all-ones during Update-DR.

Problem Fix / Workaround

- If ATmega128 is the only device in the scan chain, the problem is not visible.
- Select the Device ID Register of the ATmega128 by issuing the IDCODE instruction or by entering the Test-Logic-Reset state of the TAP controller to read out the contents of its Device ID Register and possibly data from succeeding devices of the scan chain. Issue the BYPASS instruction to the ATmega128 while reading the Device ID Registers of preceding devices of the boundary scan chain.
- If the Device IDs of all devices in the boundary scan chain must be captured simultaneously, the ATmega128 must be the fist device in the chain.

6. Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request.

Reading EEPROM by using the ST or STS command to set the EERE bit in the EECR register triggers an unexpected EEPROM interrupt request.

Problem Fix / Workaround

Always use OUT or SBI to set EERE in EECR.

ATmega128 Rev. L

- First Analog Comparator conversion may be delayed
- Interrupts may be lost when writing the timer registers in the asynchronous timer
- Stabilizing time needed when changing XDIV Register
- Stabilizing time needed when changing OSCCAL Register
- IDCODE masks data from TDI input
- · Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request

1. First Analog Comparator conversion may be delayed

If the device is powered by a slow rising V_{CC} , the first Analog Comparator conversion will take longer than expected on some devices.

Problem Fix/Workaround

When the device has been powered or reset, disable then enable the Analog Comparator before the first conversion.

2. Interrupts may be lost when writing the timer registers in the asynchronous timer

If one of the timer registers which is synchronized to the asynchronous timer2 clock is written in the cycle before a overflow interrupt occurs, the interrupt may be lost.

Problem Fix/Workaround

Always check that the Timer2 Timer/Counter register, TCNT2, does not have the value 0xFF before writing the Timer2 Control Register, TCCR2, or Output Compare Register, OCR2





3. Stabilizing time needed when changing XDIV Register

After increasing the source clock frequency more than 2% with settings in the XDIV register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The NOP instruction will always be executed correctly also right after a frequency change. Thus, the next 8 instructions after the change should be NOP instructions. To ensure this, follow this procedure:

- 1.Clear the I bit in the SREG Register.
- 2.Set the new pre-scaling factor in XDIV register.
- 3. Execute 8 NOP instructions
- 4.Set the I bit in SREG

This will ensure that all subsequent instructions will execute correctly.

Assembly Code Example:

```
CLI
                   ; clear global interrupt enable
OUT
     XDIV, temp
                   ; set new prescale value
NOP
                   ; no operation
                   ; no operation
NOP
NOP
                   ; no operation
NOP
                   ; no operation
NOP
                   ; no operation
NOP
                   ; no operation
MOP
                   ; no operation
NOP
                   ; no operation
                   ; set global interrupt enable
SEI
```

4. Stabilizing time needed when changing OSCCAL Register

After increasing the source clock frequency more than 2% with settings in the OSCCAL register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The behavior follows errata number 3., and the same Fix / Workaround is applicable on this errata.

5. IDCODE masks data from TDI input

The JTAG instruction IDCODE is not working correctly. Data to succeeding devices are replaced by all-ones during Update-DR.

Problem Fix / Workaround

- If ATmega128 is the only device in the scan chain, the problem is not visible.
- Select the Device ID Register of the ATmega128 by issuing the IDCODE instruction or by entering the Test-Logic-Reset state of the TAP controller to read out the contents of its Device ID Register and possibly data from succeeding devices of the scan chain. Issue the BYPASS instruction to the ATmega128 while reading the Device ID Registers of preceding devices of the boundary scan chain.
- If the Device IDs of all devices in the boundary scan chain must be captured simultaneously, the ATmega128 must be the fist device in the chain.

6. Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request.

Reading EEPROM by using the ST or STS command to set the EERE bit in the EECR register triggers an unexpected EEPROM interrupt request.

Problem Fix / Workaround

Always use OUT or SBI to set EERE in EECR.

ATmega128 Rev. I

- First Analog Comparator conversion may be delayed
- Interrupts may be lost when writing the timer registers in the asynchronous timer
- Stabilizing time needed when changing XDIV Register
- Stabilizing time needed when changing OSCCAL Register
- IDCODE masks data from TDI input
- Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request

1. First Analog Comparator conversion may be delayed

If the device is powered by a slow rising V_{CC} , the first Analog Comparator conversion will take longer than expected on some devices.

Problem Fix/Workaround

When the device has been powered or reset, disable then enable the Analog Comparator before the first conversion.

2. Interrupts may be lost when writing the timer registers in the asynchronous timer

If one of the timer registers which is synchronized to the asynchronous timer2 clock is written in the cycle before a overflow interrupt occurs, the interrupt may be lost.

Problem Fix/Workaround

Always check that the Timer2 Timer/Counter register, TCNT2, does not have the value 0xFF before writing the Timer2 Control Register, TCCR2, or Output Compare Register, OCR2

3. Stabilizing time needed when changing XDIV Register

After increasing the source clock frequency more than 2% with settings in the XDIV register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The NOP instruction will always be executed correctly also right after a frequency change. Thus, the next 8 instructions after the change should be NOP instructions. To ensure this, follow this procedure:

- 1.Clear the I bit in the SREG Register.
- 2.Set the new pre-scaling factor in XDIV register.
- 3. Execute 8 NOP instructions
- 4.Set the I bit in SREG

This will ensure that all subsequent instructions will execute correctly.





Assembly Code Example:

```
CLI
                   ; clear global interrupt enable
OUT
     XDIV, temp
                   ; set new prescale value
NOP
                   ; no operation
SEI
                   ; clear global interrupt enable
```

4. Stabilizing time needed when changing OSCCAL Register

After increasing the source clock frequency more than 2% with settings in the OSCCAL register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The behavior follows errata number 3., and the same Fix / Workaround is applicable on this errata.

5. IDCODE masks data from TDI input

The JTAG instruction IDCODE is not working correctly. Data to succeeding devices are replaced by all-ones during Update-DR.

Problem Fix / Workaround

- If ATmega128 is the only device in the scan chain, the problem is not visible.
- Select the Device ID Register of the ATmega128 by issuing the IDCODE instruction or by entering the Test-Logic-Reset state of the TAP controller to read out the contents of its Device ID Register and possibly data from succeeding devices of the scan chain. Issue the BYPASS instruction to the ATmega128 while reading the Device ID Registers of preceding devices of the boundary scan chain.
- If the Device IDs of all devices in the boundary scan chain must be captured simultaneously, the ATmega128 must be the fist device in the chain.

Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request.

Reading EEPROM by using the ST or STS command to set the EERE bit in the EECR register triggers an unexpected EEPROM interrupt request.

Problem Fix / Workaround

Always use OUT or SBI to set EERE in EECR.

ATmega128 Rev. H

- First Analog Comparator conversion may be delayed
- Interrupts may be lost when writing the timer registers in the asynchronous timer
- Stabilizing time needed when changing XDIV Register
- Stabilizing time needed when changing OSCCAL Register
- IDCODE masks data from TDI input
- Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request

1. First Analog Comparator conversion may be delayed

If the device is powered by a slow rising V_{CC} , the first Analog Comparator conversion will take longer than expected on some devices.

Problem Fix/Workaround

When the device has been powered or reset, disable then enable the Analog Comparator before the first conversion.

2. Interrupts may be lost when writing the timer registers in the asynchronous timer

If one of the timer registers which is synchronized to the asynchronous timer2 clock is written in the cycle before a overflow interrupt occurs, the interrupt may be lost.

Problem Fix/Workaround

Always check that the Timer2 Timer/Counter register, TCNT2, does not have the value 0xFF before writing the Timer2 Control Register, TCCR2, or Output Compare Register, OCR2

3. Stabilizing time needed when changing XDIV Register

After increasing the source clock frequency more than 2% with settings in the XDIV register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The NOP instruction will always be executed correctly also right after a frequency change. Thus, the next 8 instructions after the change should be NOP instructions. To ensure this, follow this procedure:

- 1.Clear the I bit in the SREG Register.
- 2.Set the new pre-scaling factor in XDIV register.
- 3. Execute 8 NOP instructions
- 4.Set the I bit in SREG

This will ensure that all subsequent instructions will execute correctly.

Assembly Code Example:

```
CLIT
                   ; clear global interrupt enable
OUT
     XDIV, temp
                   ; set new prescale value
NOP
                   ; no operation
                   ; no operation
NOP
                   ; no operation
NOP
NOP
                   : no operation
SET
                   ; clear global interrupt enable
```

4. Stabilizing time needed when changing OSCCAL Register

After increasing the source clock frequency more than 2% with settings in the OSCCAL register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The behavior follows errata number 3., and the same Fix / Workaround is applicable on this errata.





5. IDCODE masks data from TDI input

The JTAG instruction IDCODE is not working correctly. Data to succeeding devices are replaced by all-ones during Update-DR.

Problem Fix / Workaround

- If ATmega128 is the only device in the scan chain, the problem is not visible.
- Select the Device ID Register of the ATmega128 by issuing the IDCODE instruction or by entering the Test-Logic-Reset state of the TAP controller to read out the contents of its Device ID Register and possibly data from succeeding devices of the scan chain. Issue the BYPASS instruction to the ATmega128 while reading the Device ID Registers of preceding devices of the boundary scan chain.
- If the Device IDs of all devices in the boundary scan chain must be captured simultaneously, the ATmega128 must be the fist device in the chain.

6. Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request.

Reading EEPROM by using the ST or STS command to set the EERE bit in the EECR register triggers an unexpected EEPROM interrupt request.

Problem Fix / Workaround

Always use OUT or SBI to set EERE in EECR.

- ATmega128 Rev. G First Analog Comparator conversion may be delayed
 - Interrupts may be lost when writing the timer registers in the asynchronous timer
 - Stabilizing time needed when changing XDIV Register
 - . Stabilizing time needed when changing OSCCAL Register
 - IDCODE masks data from TDI input
 - Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request

1. First Analog Comparator conversion may be delayed

If the device is powered by a slow rising V_{CC} , the first Analog Comparator conversion will take longer than expected on some devices.

Problem Fix/Workaround

When the device has been powered or reset, disable then enable the Analog Comparator before the first conversion.

2. Interrupts may be lost when writing the timer registers in the asynchronous timer

If one of the timer registers which is synchronized to the asynchronous timer2 clock is written in the cycle before a overflow interrupt occurs, the interrupt may be lost.

Problem Fix/Workaround

Always check that the Timer2 Timer/Counter register, TCNT2, does not have the value 0xFF before writing the Timer2 Control Register, TCCR2, or Output Compare Register, OCR2

3. Stabilizing time needed when changing XDIV Register

After increasing the source clock frequency more than 2% with settings in the XDIV register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The NOP instruction will always be executed correctly also right after a frequency change. Thus, the next 8 instructions after the change should be NOP instructions. To ensure this, follow this procedure:

- 1.Clear the I bit in the SREG Register.
- 2.Set the new pre-scaling factor in XDIV register.
- 3.Execute 8 NOP instructions
- 4.Set the I bit in SREG

This will ensure that all subsequent instructions will execute correctly.

Assembly Code Example:

```
CLIT
                   ; clear global interrupt enable
OUT
     XDIV, temp
                   ; set new prescale value
                   ; no operation
NOP
NOP
                   ; no operation
SEI
                   ; set global interrupt enable
```

4. Stabilizing time needed when changing OSCCAL Register

After increasing the source clock frequency more than 2% with settings in the OSCCAL register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The behavior follows errata number 3., and the same Fix / Workaround is applicable on this errata.

5. IDCODE masks data from TDI input

The JTAG instruction IDCODE is not working correctly. Data to succeeding devices are replaced by all-ones during Update-DR.

Problem Fix / Workaround

- If ATmega128 is the only device in the scan chain, the problem is not visible.
- Select the Device ID Register of the ATmega128 by issuing the IDCODE instruction or by entering the Test-Logic-Reset state of the TAP controller to read out the contents of its Device ID Register and possibly data from succeeding devices of the scan chain. Issue the BYPASS instruction to the ATmega128 while reading the Device ID Registers of preceding devices of the boundary scan chain.
- If the Device IDs of all devices in the boundary scan chain must be captured simultaneously, the ATmega128 must be the fist device in the chain.

Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request.

Reading EEPROM by using the ST or STS command to set the EERE bit in the EECR register triggers an unexpected EEPROM interrupt request.

Problem Fix / Workaround

Always use OUT or SBI to set EERE in EECR.





ATmega128 Rev. F

- First Analog Comparator conversion may be delayed
- · Interrupts may be lost when writing the timer registers in the asynchronous timer
- Stabilizing time needed when changing XDIV Register
- Stabilizing time needed when changing OSCCAL Register
- IDCODE masks data from TDI input
- Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request

First Analog Comparator conversion may be delayed

If the device is powered by a slow rising V_{CC} , the first Analog Comparator conversion will take longer than expected on some devices.

Problem Fix/Workaround

When the device has been powered or reset, disable then enable the Analog Comparator before the first conversion.

2. Interrupts may be lost when writing the timer registers in the asynchronous timer

If one of the timer registers which is synchronized to the asynchronous timer2 clock is written in the cycle before a overflow interrupt occurs, the interrupt may be lost.

Problem Fix/Workaround

Always check that the Timer2 Timer/Counter register, TCNT2, does not have the value 0xFF before writing the Timer2 Control Register, TCCR2, or Output Compare Register, OCR2

3. Stabilizing time needed when changing XDIV Register

After increasing the source clock frequency more than 2% with settings in the XDIV register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The NOP instruction will always be executed correctly also right after a frequency change. Thus, the next 8 instructions after the change should be NOP instructions. To ensure this, follow this procedure:

- 1.Clear the I bit in the SREG Register.
- 2.Set the new pre-scaling factor in XDIV register.
- 3. Execute 8 NOP instructions
- 4.Set the I bit in SREG

This will ensure that all subsequent instructions will execute correctly.

Assembly Code Example:

```
CLI
                   ; clear global interrupt enable
OUT
     XDIV, temp
                   ; set new prescale value
NOP
                   ; no operation
                   ; no operation
NOP
SEI
                   ; set global interrupt enable
```

4. Stabilizing time needed when changing OSCCAL Register

After increasing the source clock frequency more than 2% with settings in the OSCCAL register, the device may execute some of the subsequent instructions incorrectly.

Problem Fix / Workaround

The behavior follows errata number 3., and the same Fix / Workaround is applicable on this errata.

5. IDCODE masks data from TDI input

The JTAG instruction IDCODE is not working correctly. Data to succeeding devices are replaced by all-ones during Update-DR.

Problem Fix / Workaround

- If ATmega128 is the only device in the scan chain, the problem is not visible.
- Select the Device ID Register of the ATmega128 by issuing the IDCODE instruction or by entering the Test-Logic-Reset state of the TAP controller to read out the contents of its Device ID Register and possibly data from succeeding devices of the scan chain. Issue the BYPASS instruction to the ATmega128 while reading the Device ID Registers of preceding devices of the boundary scan chain.
- If the Device IDs of all devices in the boundary scan chain must be captured simultaneously, the ATmega128 must be the fist device in the chain.

6. Reading EEPROM by using ST or STS to set EERE bit triggers unexpected interrupt request.

Reading EEPROM by using the ST or STS command to set the EERE bit in the EECR register triggers an unexpected EEPROM interrupt request.

Problem Fix / Workaround

Always use OUT or SBI to set EERE in EECR.





Datasheet Revision History

Please note that the referring page numbers in this section are referred to this document. The referring revision in this section are referring to the document revision.

Changes from Rev. 2467O-10/06 to Rev. 2467P-08/07

- 1. Updated "Features" on page 1.
- 2. Added "Data Retention" on page 8.
- 3. Updated Table 60 on page 134 and Table 95 on page 235.
- 4. Updated "C Code Example(1)" on page 177.
- 5. Updated Figure 114 on page 238.
- 6. Updated "XTAL Divide Control Register XDIV" on page 37.
- 7. Updated "Errata" on page 18.
- 8. Updated Table 34 on page 77.
- 9. Updated "Slave Mode" on page 167.

Changes from Rev. 2467N-03/06 to

1. Added note to "Timer/Counter Oscillator" on page 44.

Rev. 2467O-10/06

- 2. Updated "Fast PWM Mode" on page 125.
- 3. Updated Table 52 on page 105, Table 54 on page 105, Table 59 on page 134, Table 61 on page 135, Table 64 on page 157, and Table 66 on page 158.
- 4. Updated "Errata" on page 18.

Changes from Rev. 2467M-11/04 to Rev. 2467N-03/06

- 1. Updated note for Figure 1 on page 2.
- 2. Updated "Alternate Functions of Port D" on page 78.
- 3. Updated "Alternate Functions of Port G" on page 85.
- 4. Updated "Phase Correct PWM Mode" on page 101.
- 5. Updated Table 59 on page 134, Table 60 on page 134.
- 6. Updated "Bit 2 TOV3: Timer/Counter3, Overflow Flag" on page 142.
- 7. Updated "Serial Peripheral Interface SPI" on page 163.
- 8. Updated Features in "Analog to Digital Converter" on page 230
- 9. Added note in "Input Channel and Gain Selections" on page 243.
- 10. Updated "Errata" on page 18.

Changes from Rev. 2467L-05/04 to Rev.

2467M-11/04

- 1. Removed "analog ground", replaced by "ground".
- 2. Updated Table 11 on page 41, Table 114 on page 285, Table 128 on page 303, and Table 132 on page 320. Updated Figure 114 on page 238.
- 3. Added note to "Port C (PC7..PC0)" on page 5.
- 4. Updated "Ordering Information" on page 15.

Changes from Rev. 2467K-03/04 to Rev.

2467L-05/04

- 1. Removed "Preliminary" and "TBD" from the datasheet, replaced occurrences of ICx with ICPx.
- 2. Updated Table 8 on page 39, Table 19 on page 51, Table 22 on page 57, Table 96 on page 242, Table 126 on page 299, Table 128 on page 303, Table 132 on page 320, and Table 134 on page 322.
- 3. Updated "External Memory Interface" on page 26.
- 4. Updated "Device Identification Register" on page 253.
- 5. Updated "Electrical Characteristics" on page 318.
- 6. Updated "ADC Characteristics" on page 324.
- 7. Updated "ATmega128 Typical Characteristics" on page 332.
- 8. Updated "Ordering Information" on page 15.

Changes from Rev. 2467J-12/03 to Rev.

2467K-03/04

1. Updated "Errata" on page 18.

Changes from Rev. 2467I-09/03 to Rev. 2467J-12/03

Changes from Rev. 1. Updated "Calibrated Internal RC Oscillator" on page 42.

Changes from Rev. 2467H-02/03 to Rev. 2467I-09/03

- 1. Updated note in "XTAL Divide Control Register XDIV" on page 37.
- 2. Updated "JTAG Interface and On-chip Debug System" on page 49.
- 3. Updated values for V_{BOT} (BODLEVEL = 1) in Table 19 on page 51.
- 4. Updated "Test Access Port TAP" on page 246 regarding JTAGEN.
- Updated description for the JTD bit on page 255.
- 6. Added a note regarding JTAGEN fuse to Table 118 on page 288.
- 7. Updated R_{PU} values in "DC Characteristics" on page 318.





8. Added a proposal for solving problems regarding the JTAG instruction IDCODE in "Errata" on page 18.

Changes from Rev. 2467G-09/02 to Rev. 2467H-02/03

- 1. Corrected the names of the two Prescaler bits in the SFIOR Register.
- 2. Added Chip Erase as a first step under "Programming the Flash" on page 315 and "Programming the EEPROM" on page 316.
- 3. Removed reference to the "Multipurpose Oscillator" application note and the "32 kHz Crystal Oscillator" application note, which do not exist.
- 4. Corrected OCn waveforms in Figure 52 on page 126.
- 5. Various minor Timer1 corrections.
- 6. Added information about PWM symmetry for Timer0 and Timer2.
- 7. Various minor TWI corrections.
- 8. Added reference to Table 124 on page 292 from both SPI Serial Programming and Self Programming to inform about the Flash Page size.
- 9. Added note under "Filling the Temporary Buffer (Page Loading)" on page 280 about writing to the EEPROM during an SPM Page load.
- 10. Removed ADHSM completely.
- 11. Added section "EEPROM Write During Power-down Sleep Mode" on page 25.
- 12. Updated drawings in "Packaging Information" on page 16.

Changes from Rev. 2467F-09/02 to Rev. 2467G-09/02

1. Changed the Endurance on the Flash to 10,000 Write/Erase Cycles.

Changes from Rev. 2467E-04/02 to Rev. 2467F-09/02

- 1. Added 64-pad QFN/MLF Package and updated "Ordering Information" on page 15.
- 2. Added the section "Using all Locations of External Memory Smaller than 64 KB" on page 33.
- 3. Added the section "Default Clock Source" on page 38.
- 4. Renamed SPMCR to SPMCSR in entire document.
- When using external clock there are some limitations regards to change of frequency.
 This is descried in "External Clock" on page 43 and Table 131, "External Clock Drive," on page 320.
- 6. Added a sub section regarding OCD-system and power consumption in the section "Minimizing Power Consumption" on page 48.

7. Corrected typo (WGM-bit setting) for:

"Fast PWM Mode" on page 99 (Timer/Counter0).

"Phase Correct PWM Mode" on page 101 (Timer/Counter0).

"Fast PWM Mode" on page 151 (Timer/Counter2).

"Phase Correct PWM Mode" on page 153 (Timer/Counter2).

- 8. Corrected Table 81 on page 192 (USART).
- 9. Corrected Table 102 on page 259 (Boundary-Scan)
- 10. Updated Vil parameter in "DC Characteristics" on page 318.

Changes from Rev. 2467D-03/02 to Rev. 2467E-04/02

- Updated the Characterization Data in Section "ATmega128 Typical Characteristics" on page 332.
- 2. Updated the following tables:

Table 19 on page 51, Table 20 on page 55, Table 68 on page 158, Table 102 on page 259, and Table 136 on page 328.

3. Updated Description of OSCCAL Calibration Byte.

In the data sheet, it was not explained how to take advantage of the calibration bytes for 2, 4, and 8 MHz Oscillator selections. This is now added in the following sections:

Improved description of "Oscillator Calibration Register – OSCCAL" on page 42 and "Calibration Byte" on page 289.

Changes from Rev. 2467C-02/02 to Rev. 2467D-03/02

- 1. Added more information about "ATmega103 Compatibility Mode" on page 5.
- 2. Updated Table 2, "EEPROM Programming Time," on page 23.
- 3. Updated typical Start-up Time in Table 7 on page 38, Table 9 and Table 10 on page 40, Table 12 on page 41, Table 14 on page 42, and Table 16 on page 43.
- 4. Updated Table 22 on page 57 with typical WDT Time-out.
- Corrected description of ADSC bit in "ADC Control and Status Register A ADCSRA" on page 244.
- 6. Improved description on how to do a polarity check of the ADC differential results in "ADC Conversion Result" on page 241.
- 7. Corrected JTAG version numbers in "JTAG Version Numbers" on page 256.
- 8. Improved description of addressing during SPM (usage of RAMPZ) on "Addressing the Flash During Self-Programming" on page 278, "Performing Page Erase by SPM" on page 280, and "Performing a Page Write" on page 280.
- 9. Added not regarding OCDEN Fuse below Table 118 on page 288.





10. Updated Programming Figures:

Figure 135 on page 290 and Figure 144 on page 301 are updated to also reflect that AVCC must be connected during Programming mode. Figure 139 on page 297 added to illustrate how to program the fuses.

- 11. Added a note regarding usage of the PROG_PAGELOAD and PROG PAGEREAD instructions on page 307.
- 12. Added Calibrated RC Oscillator characterization curves in section "ATmega128 Typical Characteristics" on page 332.
- 13. Updated "Two-wire Serial Interface" section.

More details regarding use of the TWI Power-down operation and using the TWI as master with low TWBRR values are added into the data sheet. Added the note at the end of the "Bit Rate Generator Unit" on page 204. Added the description at the end of "Address Match Unit" on page 205.

14. Added a note regarding usage of Timer/Counter0 combined with the clock. See "XTAL Divide Control Register – XDIV" on page 37.

Changes from Rev. 2467B-09/01 to Rev. 2467C-02/02

1. Corrected Description of Alternate Functions of Port G

Corrected description of TOSC1 and TOSC2 in "Alternate Functions of Port G" on page 85.

2. Added JTAG Version Numbers for rev. F and rev. G

Updated Table 100 on page 256.

3 Added Some Preliminary Test Limits and Characterization Data

Removed some of the TBD's in the following tables and pages:

Table 19 on page 51, Table 20 on page 55, "DC Characteristics" on page 318, Table 131 on page 320, Table 134 on page 322, and Table 136 on page 328.

- 4. Corrected "Ordering Information" on page 15.
- 5. Added some Characterization Data in Section "ATmega128 Typical Characteristics" on page 332.
- 6. Removed Alternative Algortihm for Leaving JTAG Programming Mode.

See "Leaving Programming Mode" on page 315.

7. Added Description on How to Access the Extended Fuse Byte Through JTAG Programming Mode.

See "Programming the Fuses" on page 317 and "Reading the Fuses and Lock Bits" on page 317.



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